

<b>Notice of References Cited</b>	Application/Control No. 10/716,307	Applicant(s)/Patent Under Reexamination YERIAN ET AL.	
	Examiner Maria Veronica D. Ewald	Art Unit 1722	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-3,645,505	02-1972	McLeod et al.	366/160.3
*	B	US-5,593,707	01-1997	Goe et al.	425/257
*	C	US-6,380,517	04-2002	Morgan, Allan C.	219/389
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	K	US-			
	L	US-			
	M	US-			

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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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